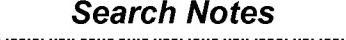


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/628,271	LEE ET AL.	
	Examiner	Art Unit	
	Helen C. Kwok	2856	

INTERFERENCE SEARCHED			
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73	504.13	11/3/2010	HK
73	504.18	11/3/2010	HK